

INTERNATIONAL JOURNALS

- 1) **H.K.E Latha**, A. Udayakumar, V.Siddeswara Prasad (2015), “Microstructure and electrical properties of nitrogen doped 3C-SiC thin films deposited using methyltrichlorosilane”, *Journal of Materials science in semiconductor processing*, Vol.29, PP 117- 123.
- 2) **H.K.E Latha**, A. Udayakumar, V.Siddeswara Prasad, (2014) “Effect of nitrogen doping on elastic modulus and hardness of 3C-SiC thin films deposited using methyltrichlorosilane”, **Journal of Materials research express**, DOI:10.1088/2053-1591/1/1/015902.
- 3) **H.K.E Latha**, A. Udayakumar, V.Siddeswara Prasad, (2014) “ Effect of nitrogen doping on the electrical properties of 3C-SiC thin films for high temperature sensors applications”, **Journal of Acta metallurgica sinica (English Letters)**, Vol.27, Issue 1, pp, February 2014, 168-174.
- 4) **H.K.E Latha**, A. Udayakumar, V.Siddeswara Prasad, (2013) “Growth and effect of deposition pressure on microstructure and electrical properties of 3C-SiC thin films deposited using MTS single precursor”, **International Journal of thin films science and technology**, Vol.2 No.3, pp. 163-170.
- 5) **H M Kalpana** ,V Siddeswara Prasad and M.M Nayak, “Influence of annealing and thickness on the electrical properties of invar36 thin film for Strain gauge applications”, **International Journal of Thin Films Science & Technology**, Vol. 3, pp. 155-161, 2013.
- 6) H M Kalpana ,V Siddeswara Prasad (2014). “Development of the invar36 thin film strain gauge sensor for strain measurement”,*Measurement Science and Technology*,vol.25,pp.1-7. doi:10.1088/0957-0233/25/6/065102, IOP Publishing

Conferences

- 1) Dr. V. Siddeswara Prasad and Dr. J. Nagaraju “**An Experimental Study to show the behavior of Electrical Contact Resistance and Coefficient of Friction at Low Current Sliding Electrical interfaces**” 57th IEEE Holm International Conference on Electrical Contacts held at Crown Plaza Northstar Hotel, Minneapolis, MN, USA. During 11th to 14th Sep 2011 , Page Nos. 254-260

- 2) **Latha H K E**, A Udayakumar, V Siddeswara Prasad (2013) “Growth and characterization of undoped and nitrogen doped 3C-SiC thin films deposited using methyltrichlorosilane for sensor applications”, **National Symposium on Instrumentation (NSI-38)**, October 24-26, 2013, B.V.B.College of Engineering & Technology, Hubli, pp.104.
- 3) **Latha H K E**, A Udayakumar, V Siddeswara Prasad, (2013) “Structural and electrical properties of undoped and nitrogen doped 3C-SiC thin films deposited using methyltrichlorosilane”, **International Conference on communication, VLSi and Signal processing (ICCVSP-2013)**, 20th-22nd Feb’2013,SIT, Tumkur, pp. 304-308.
- 4) **H M Kalpana** and V Siddeswara Prasad, “Development of INVAR36 thin Films for Strain Guage Applications”, **International Conference on Communication, VLSI & Signal Processing** held at Siddaganga Institute of Technology, Tumkur. From 20th to 22nd February 2013, pp 300-303.
- 5) **H M Kalpana** and V Siddeswara Prasad, Annealing Effects on Electrical Properties of DC Sputtered Invar36 Thin Film for Strain Gauge Applications, **National Symposium on Instrumentation (NSI-38)** held at KLE Society’s BVB College of Engineering & Technology, Vidyanagar, Hubli-580031,Karnataka. From 24th to 26th October 2013, pp 103.